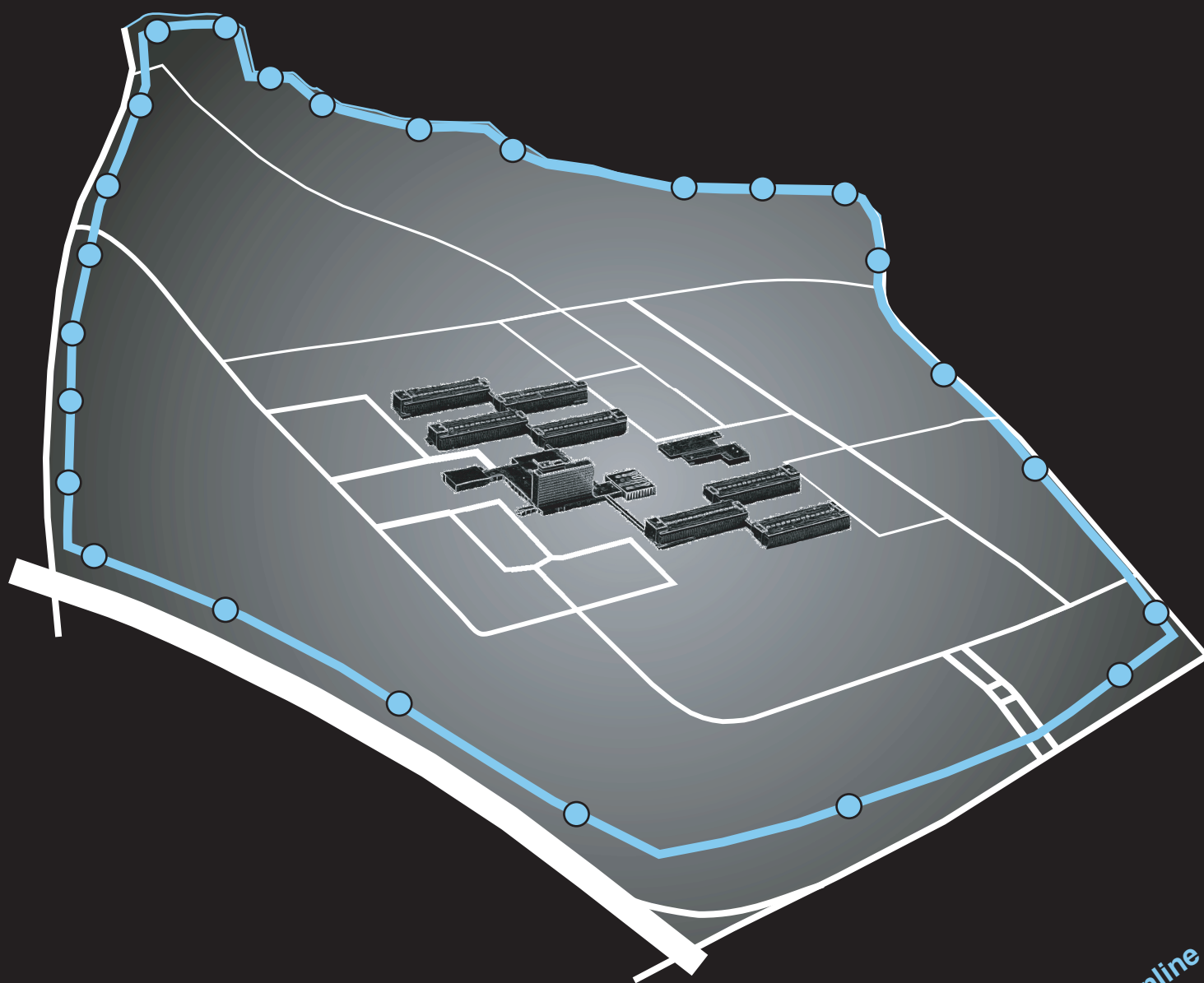


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NIST

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- Computer Security
- Information Access
- Convergent Information Systems
- Information Services and Computing
- Software Diagnostics and Conformance Testing
- Statistical Engineering

¹ At Boulder, CO 80303.

² Some elements at Boulder, CO.

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Cover: The cover illustration shows the placement of radiation monitors (solid blue circles) around the perimeter of the NIST Gaithersburg site. Radiation and radioactive materials are generated and used in a variety of NIST operations. A continuing program of radiation monitoring, beginning before occupancy of the Gaithersburg site in the early 1960s, is described in the paper by Hobbs (see p. 781). Cover illustration by C. Carey.

The *Journal of Research of the National Institute of Standards and Technology*, the flagship periodic publication of the national metrology institute of the United States, features advances in metrology and related fields of physical science, engineering, applied mathematics, statistics, biotechnology, and information technology that reflect the scientific and technical programs of the Institute. The *Journal* publishes papers on instrumentation for making accurate measurements, mathematical models of physical phenomena, including computational models, critical data, calibration techniques, well-characterized reference materials, and quality assurance programs that report the results of current NIST work in these areas. Occasionally, a Special Issue of the *Journal* is devoted to papers on a single topic. Also appearing on occasion are review articles and reports on conferences and workshops sponsored in whole or in part by NIST.

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